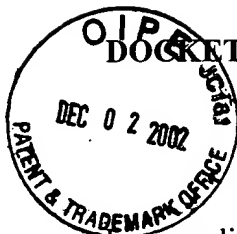


2123



DOCKET NO. KAPUR 5-10

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Sharad Kapur, *et al.*

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Serial No.: 09/427,238
Filed: October 26, 1999
For: SYSTEM AND METHOD FOR DETERMINING CAPACITANCE FOR
LARGE-SCALE INTEGRATED CIRCUITS
Group No.: 2123
Examiner: Eduardo Garcia-Otero

Commissioner for Patents
Washington, D. C. 20231

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on
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EDITH SHEIC
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Edith Sheic
(Signature of the person signing the certificate)

Sir:

AMENDMENT UNDER 37 C.F.R. § 1.111

The Applicants have carefully considered this application in connection with the Examiner's Action mailed on August 27, 2002, and respectfully request reconsideration of this application in view of the following amendment and remarks.